

ELECTRICAL CHARACTERISTICS

PLESSEY SEMICONDUCTORS

Test Conditions (unless otherwise stated):
 Test circuit Fig (4)
 Frequency 60 MHz
 Supply voltage 9 volts
 Ambient temperature $22 \pm 2^\circ\text{C}$

Characteristic	Value			Units	Conditions
	Min	Typ	Max		
Small signal voltage gain	8	10	12	dB	$V_{in} = -30 \text{ dBm}$
High level slope gain	-1	0	+1	dB	
Upper cut off frequency	250	500		MHz	
Lower cut off frequency		3	10	MHz	-3dB w.r.t. $\pm 60 \text{ MHz}$
Supply current		17	26	mA	
Phase change with input amplitude		1.1	3	degrees	$-V_{in} = 30 \text{ dBm}$ to $+10 \text{ dBm}$
Input impedance	2.5pF parallel with 1k Ω				$f = 10 - 200 \text{ MHz}$
Output impedance	15 Ω series with 25nH				

OPERATING NOTES

1. Supply Voltage Options

An on chip resistor is provided which can be used to drop the supply voltage instead of the external 180 ohms shown in the test circuit. The extra dissipation in this resistor reduces the maximum ambient operating temperature to 100°C . It is also possible to use a 6 volt supply connected directly to pins 1 and 2. Problems with feedback on the supply line etc may occur in this connection and RF chokes may be required in the supply line between stages.

2. Layout Precautions

The internal decoupling capacitors help prevent high frequency instability, however normal high frequency layout precautions are still necessary. Coupling capacitors should be physically small and be connected with short leads. It is most important that the ground connections are made with short leads to a continuous ground plane.

3. Low Frequency Response

The LF response is determined by the on chip capacitors. It can be extended by extra external decoupling on pins 5 and 1.

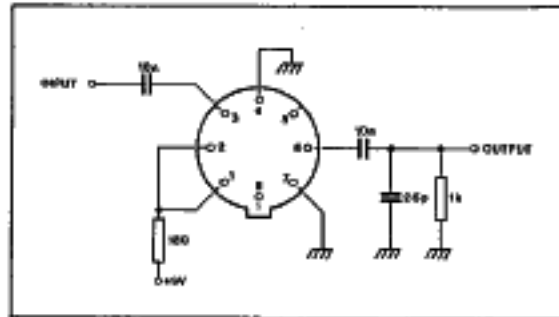


Fig. 4 Test circuit

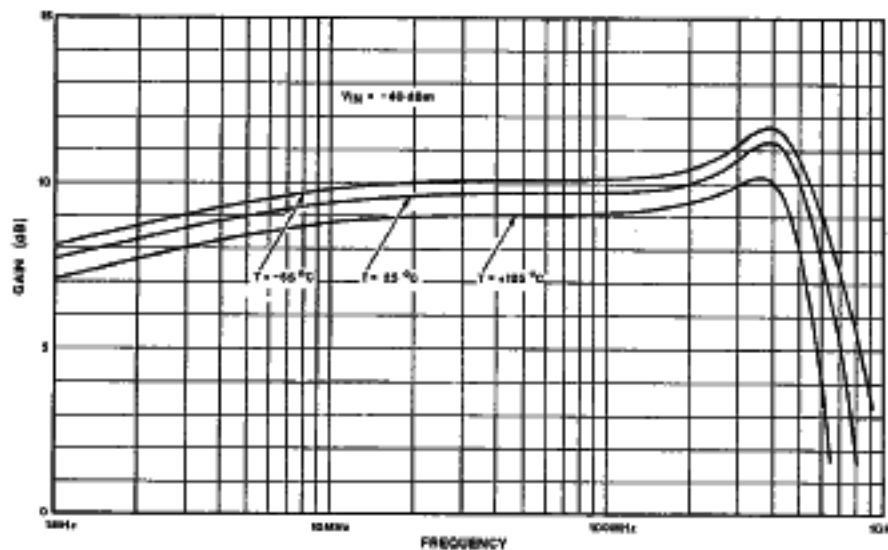


Fig. 5 Small signal frequency response